64Mbit DDR SDRAM

512K x 32Bit x 4 Banks

Double Data Rate Synchronous RAM
with Bi-directional Data Strobe and DLL
(144-Ball FBGA)

Revision 1.2 September 2001

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Revision History

Revision 1.2 (September 1, 2001)

- Added K4D623238B-GL* as a low power part (ICC6=1mA)
- Added ICC7 (Operating current at 4bank interleaving)
- Added 100MHz@CL2

Revision 1.1 (August 2, 2001)

• Changed tCK(max) of K4D623238B-GC45/-50/-55/-60 from 7ns to 10ns.

Revision 1.0 (June 22, 2001)

• Changed VDD/VDDQ of K4D623238B-GC33 from 2.5V to 2.8V.

Revision 0.4 (April 10,2001) - Preliminary Spec

- Added K4D623238B-GC50
- Added K4D623238B-GC55
- Added K4D623238B-GC60
- Defined tWR_A that means write recovery time @ Auto precharge.

Revision 0.3 (February 10, 2001) - Preliminary

• Changed tDAL of K4D623238B-GC45 from 6tCK to 7tCK.

Revision 0.2 (December 13, 2000) - Target Spec

• Defined Target Specification

Revision 0.0 (November 21, 2000)



512K x 32Bit x 4 Banks Double Data Rate Synchronous RAM with Bi-directional Data Strobe and DLL

FEATURES

- 2.5V ± 5% power supply for device operation
- $VDD/VDDQ = 2.8V \pm 5\%$ for -33
- $VDD/VDDQ = 2.5V \pm 5\%$ for -60/-55/-50/-45/-40
- SSTL_2 compatible inputs/outputs
- · 4 banks operation
- · MRS cycle with address key programs
 - -. Read latency 3,4,5 (clock)
 - -. Burst length (2, 4, 8 and Full page)
 - -. Burst type (sequential & interleave)
- Full page burst length for sequential burst type only
- Start address of the full page burst should be even
- All inputs except data & DM are sampled at the positive going edge of the system clock
- · Differential clock input
- No Wrtie-Interrupted by Read Function

- 4 DQSs (1DQS/Byte)
- Data I/O transactions on both edges of Data strobe
- · DLL aligns DQ and DQS transitions with Clock transition
- · Edge aligned data & data strobe output
- · Center aligned data & data strobe input
- . DM for write masking only
- · Auto & Self refresh
- 16ms refresh period (2K cycle)
- 144-Ball FBGA
- Maximum clock frequency up to 300MHz
- Maximum data rate up to 600Mbps/pin

ORDERING INFORMATION

| Part NO. | Max Freq. | Max Data Rate | Interface | Package | | | |
|-------------------|-----------|---------------|-------------|---------------|--|--|--|
| K4D623238B-GC/L33 | 300MHz | 600Mbps/pin | | | | | |
| K4D623238B-GC/L40 | 250MHz | 500Mbps/pin | - SSTL 2 | | | | |
| K4D623238B-GC/L45 | 222MHz | 444Mbps/pin | | 444 D-II FDOA | | | |
| K4D623238B-GC/L50 | 200MHz | 400Mbps/pin | 351L_2 | 144-Ball FBGA | | | |
| K4D623238B-GC/L55 | 183MHz | 366Mbps/pin | | | | | |
| K4D623238B-GC/L60 | 166MHz | 333Mbps/pin | | | | | |

GENERAL DESCRIPTION

FOR 512K x 32Bit x 4 Bank DDR SDRAM

The K4D623238 is 67,108,864 bits of hyper synchronous data rate Dynamic RAM organized as 2 x1,048,976 words by 32 bits, fabricated with SAMSUNG's high performance CMOS technology. Synchronous features with Data Strobe allow extremely high performance up to 2.4GB/s/chip. I/O transactions are possible on both edges of the clock cycle. Range of operating frequencies, programmable burst length and programmable latencies allow the device to be useful for a variety of high performance memory system applications.



PIN CONFIGURATION (Top View)

| | 2 | 3 | 4 | 5 | 6 | 7 | 8 | 9 | 10 | 11 | 12 | 13 |
|---|------|------|------|------|----------------|----------------|----------------|------------------|------------------|-------|------|------|
| В | DQS0 | DM0 | VSSQ | DQ3 | DQ2 | DQ0 | DQ31 | DQ29 | DQ28 | VSSQ | DM3 | DQS3 |
| С | DQ4 | VDDQ | NC | VDDQ | DQ1 | VDDQ | VDDQ | DQ30 | VDDQ | NC | VDDQ | DQ27 |
| D | DQ6 | DQ5 | VSSQ | VSSQ | VSSQ | VDD | VDD | VSSQ | VSSQ | VSSQ | DQ26 | DQ25 |
| E | DQ7 | VDDQ | VDD | VSS | VSSQ | VSS | VSS | VSSQ | VSS | VDD | VDDQ | DQ24 |
| F | DQ17 | DQ16 | VDDQ | VSSQ | VSS Thermal | VSS Thermal | VSS Thermal | VSS Thermal | VSSQ | VDDQ | DQ15 | DQ14 |
| G | DQ19 | DQ18 | VDDQ | VSSQ | VSS Thermal | VSS Thermal | VSS Thermal | VSS Thermal | VSSQ | VDDQ | DQ13 | DQ12 |
| н | DQS2 | DM2 | NC | VSSQ | VSS Thermal | VSS Thermal | VSS Thermal | VSS Thermal | VSSQ | NC | DM1 | DQS1 |
| J | DQ21 | DQ20 | VDDQ | VSSQ | VSS Thermal | VSS Thermal | VSS Thermal | VSS Thermal | VSSQ | VDDQ | DQ11 | DQ10 |
| K | DQ22 | DQ23 | VDDQ | VSSQ | VSS | VSS | VSS | VSS | VSSQ | VDDQ | DQ9 | DQ8 |
| L | CAS | WE | VDD | VSS | A10 | VDD | VDD | RFU ₁ | VSS | VDD | NC | NC |
| М | RAS | NC | NC | BA1 | A2 | RFU3 | A9 | A5 | RFU ₂ | СК | CK | MCL |
| N | CS | NC | BA0 | A0 | A1 | А3 | A4 | A6 | A7 | A8/AP | CKE | VREF |
| | | | | | | | | | | | | |

NOTE:

- 1. RFU1 is reserved for A12
- 2. RFU2 is reserved for BA2
- 3. RFU3 is reserved for A11
- 4. VSS Thermal balls are optional

PIN DESCRIPTION

| CK, CK | Differential Clock Input | BA0, BA1 | Bank Select Address |
|-------------------|--------------------------|------------|---------------------|
| CKE | Clock Enable | A0 ~A10 | Address Input |
| CS | Chip Select | DQ0 ~ DQ31 | Data Input/Output |
| RAS | Row Address Strobe | VDD | Power |
| CAS | Column Address Strobe | Vss | Ground |
| WE | Write Enable | VDDQ | Power for DQ's |
| DQS | Data Strobe | Vssq | Ground for DQ's |
| DM | Data Mask | NC | No Connection |
| RFU | Reserved for Future Use | MCL | Must Connect Low |



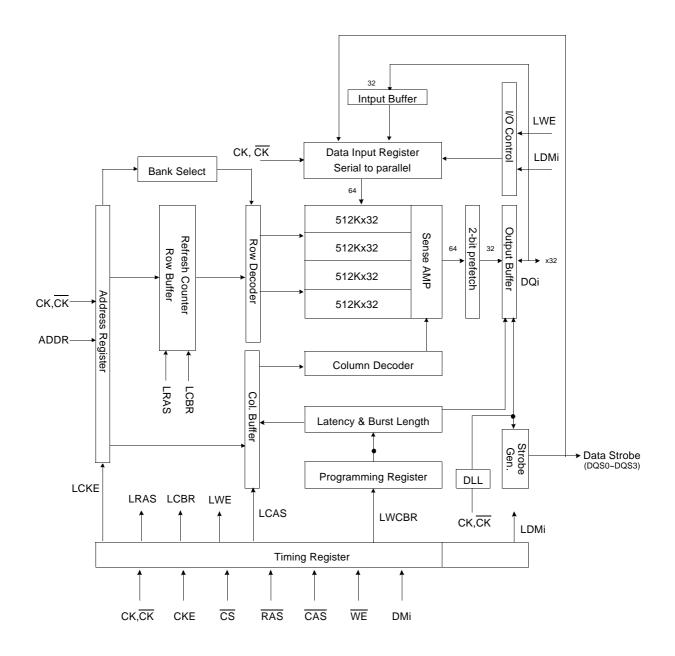
INPUT/OUTPUT FUNCTIONAL DESCRIPTION

| Symbol | Туре | Function |
|-------------|---|--|
| CK, CK*1 | Input | The differential system clock Input. All of the inputs are sampled on the rising edge of the clock except DQ's and DM's that are sampled on both edges of the DQS. |
| CKE | Input | Activates the CK signal when high and deactivates the CK signal when low. By deactivating the clock, CKE low indicates the Power down mode or Self refresh mode. |
| CS | Input | CS enables the command decoder when low and disabled the command decoder when high. When the command decoder is disabled, new commands are ignored but previous operations continue. |
| RAS | Input | Latches row addresses on the positive going edge of the CK with RAS low. Enables row access & precharge. |
| CAS | Input | Latches column addresses on the positive going edge of the CK with CAS low. Enables column access. |
| WE | Input | Enables write operation and row precharge. Latches data in starting from CAS, WE active. |
| DQS0 ~ DQS3 | Input/Output | Data input and output are synchronized with both edge of DQS. DQSo for DQ0 ~ DQ7, DQS1 for DQ8 ~ DQ15, DQS2 for DQ16 ~ DQ23, DQS3 for DQ24 ~ DQ31. |
| DMo ~ DM3 | Input | Data In mask. Data In is masked by DM Latency=0 when DM is high in burst write. DMo for DQ0 ~ DQ7, DM1 for DQ8 ~ DQ15, DM2 for DQ16 ~ DQ23, DM3 for DQ24 ~ DQ31. |
| DQ0 ~ DQ31 | Input/Output | Data inputs/Outputs are multiplexed on the same pins. |
| BAo, BA1 | Input | Selects which bank is to be active. |
| A0 ~ A10 | Input | Row/Column addresses are multiplexed on the same pins. Row addresses: RA0 ~ RA10, Column addresses: CA0 ~ CA7. Column address CA8 is used for auto precharge. |
| VDD/VSS | Power Supply | Power and ground for the input buffers and core logic. |
| VDDQ/Vssq | Power Supply | Isolated power supply and ground for the output buffers to provide improved noise immunity. |
| VREF | Power Supply | Reference voltage for inputs, used for SSTL interface. |
| NC/RFU | No connection/ Reserved for future use | This pin is recommended to be left "No connection" on the device |
| MCL | Must Connect Low | Must connect low |

^{*1 :} The timing reference point for the differential clocking is the cross point of CK and $\overline{\text{CK}}$. For any applications using the single ended clocking, apply VREF to $\overline{\text{CK}}$ pin.



BLOCK DIAGRAM (512Kbit x 32I/O x 4 Bank)



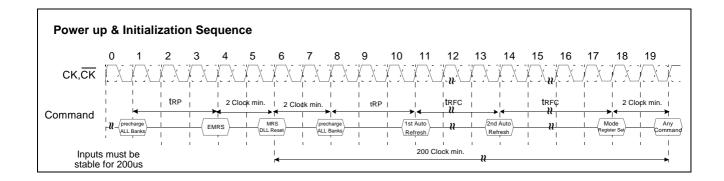


FUNCTIONAL DESCRIPTION

• Power-Up Sequence

DDR SDRAMs must be powered up and initialized in a predefined manner to prevent undefined operations.

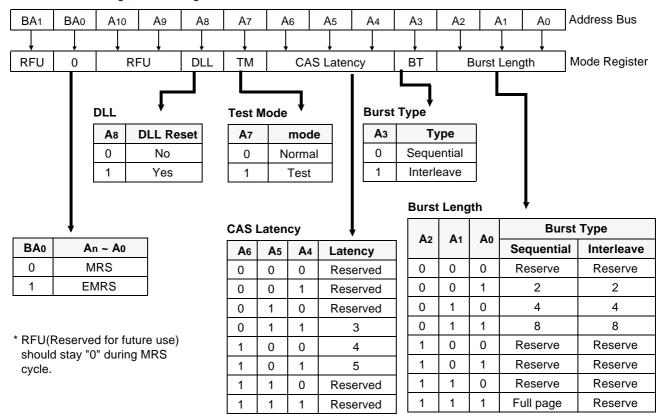
- 1. Apply power and keep CKE at low state (All other inputs may be undefined)
 - Apply VDD before VDDQ .
 - Apply VDDQ before VREF & VTT
- 2. Start clock and maintain stable condition for minimum 200us.
- 3. The minimum of 200us after stable power and clock(CK,CK), apply NOP and take CKE to be high.
- 4. Issue precharge command for all banks of the device.
- 5. Issue a EMRS command to enable DLL
- *1 6. Issue a MRS command to reset DLL. The additional 200 clock cycles are required to lock the DLL.
- *1,2 7. Issue precharge command for all banks of the device.
 - 8. Issue at least 2 or more auto-refresh commands.
 - 9. Issue a mode register set command with A8 to low to initialize the mode register.
 - *1 The additional 200cycles of clock input is required to lock the DLL after enabling DLL.
 - *2 Sequence of 6&7 is regardless of the order.

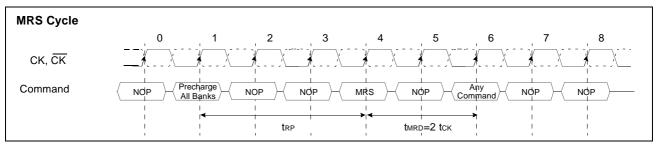




MODE REGISTER SET(MRS)

The mode register stores the data for controlling the various operating modes of DDR SDRAM. It programs CAS latency, addressing mode, burst length, test mode, DLL reset and various vendor specific options to make DDR SDRAM useful for variety of different applications. The default value of the mode register is not defined, therefore the mode register must be written after EMRS setting for proper operation. The mode register is written by asserting low on CS, RAS, CAS and WE(The DDR SDRAM should be in active mode with CKE <u>already high prior to writing</u> into the mode register). The state of address pins Ao ~ A10 and BAo, BA1 in the same cycle as CS, RAS, CAS and WE going low is written in the mode register. Minimum two clock cycles are requested to complete the write operation in the mode register. The mode register contents can be changed using the same command and clock cycle requirements during operation as long as all banks are in the idle state. The mode register is divided into various fields depending on functionality. The burst length uses A0 ~ A2, addressing mode uses A3, CAS latency(read latency from column address) uses A4 ~ A6. A7 is used for test mode. A8 is used for DLL reset. A7,A8, BA0 and BA1 must be set to low for normal MRS operation. Refer to the table for specific codes for various burst length, addressing modes and CAS latencies.





- *1 : MRS can be issued only at all banks precharge state.
- *2: Minimum tRP is required to issue MRS command.



EXTENDED MODE REGISTER SET(EMRS)

The extended mode register stores the data for enabling or disabling DLL and selecting output driver strength. The default value of the extended mode register is not defined, therefore the extened mode register must be written after power up for enabling or disabling DLL. The extended mode register is written by asserting low on CS, RAS, CAS, WE and high on BA0(The DDR SDRAM should be in all bank precharge with CKE already high prior to writing into the extended mode register). The state of address pins A0, A2 ~ A5, A7 ~ A10 and BA1 in the same cycle as CS, RAS, CAS and WE going low are written in the extended mode register. A1 and A6 are used for setting driver strength to normal, weak or matched impedance. Two clock cycles are required to complete the write operation in the extended mode register. The mode register contents can be changed using the same command and clock cycle requirements during operation as long as all banks are in the idle state. A0 is used for DLL enable or disable. "High" on BA0 is used for EMRS. All the other address pins except A0,A1,A6 and BA0 must be set to low for proper EMRS operation. Refer to the table for specific codes.

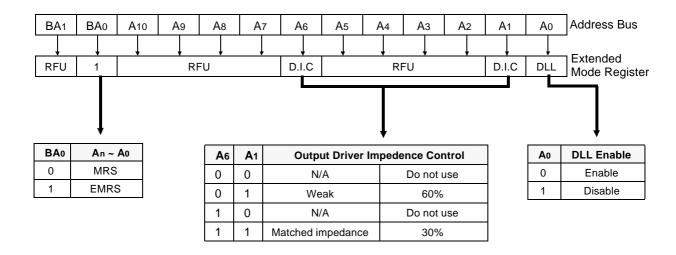


Figure 7. Extended Mode Register set



^{*} RFU(Reserved for future use) should stay "0" during EMRS cycle.

ABSOLUTE MAXIMUM RATINGS

| Parameter | Symbol | Value | Unit |
|---------------------------------------|-----------|------------|------|
| Voltage on any pin relative to Vss | VIN, VOUT | -0.5 ~ 3.6 | V |
| Voltage on VDD supply relative to Vss | VDD | -1.0 ~ 3.6 | V |
| Voltage on VDD supply relative to Vss | VDDQ | -0.5 ~ 3.6 | V |
| Storage temperature | Тѕтс | -55 ~ +150 | °C |
| Power dissipation | PD | 2.0 | W |
| Short circuit current | los | 50 | mA |

Note: Permanent device damage may occur if ABSOLUTE MAXIMUM RATINGS are exceeded.

Functional operation should be restricted to recommended operating condition.

Exposure to higher than recommended voltage for extended periods of time could affect device reliability.

POWER & DC OPERATING CONDITIONS(SSTL_2 In/Out)

Recommended operating conditions(Voltage referenced to Vss=0V, Ta=0 to 65°C)

| Parameter | Symbol | Min | Тур | Max | Unit | Note |
|---------------------------|--------|-----------|------|-----------|------|-------------|
| Device Supply voltage | VDD | 2.375 | 2.50 | 2.625 | V | 1,7 |
| Output Supply voltage | VDDQ | 2.375 | 2.50 | 2.625 | V | 1,7 |
| Device Supply voltage | VDD | 2.66 | 2.8 | 2.94 | V | 1,8 |
| Output Supply voltage | VDDQ | 2.66 | 2.8 | 2.94 | V | 1,8 |
| Reference voltage | VREF | 0.49*VDDQ | - | 0.51*VDDQ | V | 2 |
| Termination voltage | Vtt | VREF-0.04 | VREF | VREF+0.04 | V | 3 |
| Input logic high voltage | VIH | VREF+0.15 | - | VDDQ+0.30 | V | 4 |
| Input logic low voltage | VIL | -0.30 | - | VREF-0.15 | V | 5 |
| Output logic high voltage | Voн | Vtt+0.76 | - | - | V | IOH=-15.2mA |
| Output logic low voltage | Vol | - | - | Vtt-0.76 | V | IOL=+15.2mA |
| Input leakage current | lıL | -5 | - | 5 | uA | 6 |
| Output leakage current | loL | -5 | - | 5 | uA | 6 |

 ${f Note}: \ 1. \ {f Under all \ conditions \ VDDQ \ must \ be \ less \ than \ or \ equal \ to \ VDD.}$

- 2. VREF is expected to equal 0.50*VDDQ of the transmitting device and to track variations in the DC level of the same. Peak to peak noise on the VREF may not exceed + 2% of the DC value. Thus, from 0.50*VDDQ, VREF is allowed + 25mV for DC error and an additional + 25mV for AC noise.
- 3. $\mbox{\ensuremath{Vtt}}$ of the transmitting device must track $\mbox{\ensuremath{VREF}}$ of the receiving device.
- 4. VIH(max.)= VDDQ +1.5V for a pulse width and it can not be greater than 1/3 of the cycle rate.
- 5. VIL(mim.)= -1.5V for a pulse width and it can not be greater than 1/3 of the cycle rate.
- 6. For any pin under test input of 0V ≤ VIN ≤ VDD is acceptable. For all other pins that are not under test VIN=0V.
- 7. For -40/-45/-50/-55/-60, VDD/VDDQ=2.5V + 5%
- 8. For -33, VDD/VDDQ=2.8V <u>+</u> 5%



DC CHARACTERISTICS

Recommended operating conditions Unless Otherwise Noted, TA=0 to 65°C)

| Denomenton | Council of | Test Condition | | | Ver | sion | | | 11::4 | Mata |
|--|------------|--|------|-----|-----|------|-----|-----|-------|------|
| Parameter | Symbol | rest Condition | -33 | -40 | -45 | -50 | -55 | -60 | Unit | Note |
| Operating Current (One Bank Active) | ICC1 | Burst Lenth=2 $\text{tRC} \ge \text{tRC}(\text{min})$ IoL=0mA, $\text{tcc=} \text{tcc}(\text{min})$ | 470 | 340 | 315 | 290 | 275 | 260 | mA | 1 |
| Precharge Standby Current in Power-down mode | ICC2P | CKE ≤ VIL(max), tcc= tcc(min) | 75 | 65 | 65 | 65 | 65 | 65 | mA | |
| Precharge Standby Current in Non Power-down mode | ICC2N | $\label{eq:cke} \begin{split} CKE &\geq VIH(min), \; CS \geq VIH(min), \\ tcc &= tcc(min) \end{split}$ | 155 | 125 | 120 | 115 | 110 | 105 | mA | |
| Active Standby Current power-down mode | ІссзР | CKE ≤ VIL(max), tcc= tcc(min) | 150 | 130 | 130 | 130 | 130 | 130 | mA | |
| Active Standby Current in in Non Power-down mode | Icc3N | $\begin{aligned} &CKE \geq VIH(min), \; CS \geq VIH(min), \\ &tcc=tcc(min) \end{aligned}$ | 270 | 220 | 210 | 200 | 190 | 180 | mA | |
| Operating Current (Burst Mode) | ICC4 | IOL=0mA ,tcc= tcc(min), Page Burst, All Banks activated. | 900 | 700 | 650 | 600 | 550 | 520 | mA | |
| Refresh Current | ICC5 | trc≥trFc(min) | 405 | 340 | 330 | 320 | 310 | 300 | mA | 2 |
| Self Refresh Current | ICC6 | CKE ≤ 0.2V | 4.5 | | | 4 | | | mA | 3 |
| | | | | | | 1 | r | | mA | 4 |
| Operating Current (4Bank Interleaving) | ICC7 | Burst Lenth=4 tRc ≥ tRc(min) IoL=0mA, tcc= tcc(min) | 1050 | 850 | 800 | 750 | 700 | 670 | mA | |

Note: 1. Measured with outputs open.

- 2. Refresh period is 16ms.
- 3. K4D623238B-GC*
- 4. K4D623238B-GL*

AC INPUT OPERATING CONDITIONS

Recommended operating conditions (Voltage referenced to Vss=0V, VdD/ VdDq=2.5V \pm 5%, Ta=0 to 65°C)

| Parameter | Symbol | Min | Тур | Max | Unit | Note |
|---|--------|--------------|-----|--------------|------|------|
| Input High (Logic 1) Voltage; DQ | VIH | VREF+0.35 | - | - | V | |
| Input Low (Logic 0) Voltage; DQ | VIL | - | - | VREF-0.35 | V | |
| Clock Input Differential Voltage; CK and CK | VID | 0.7 | - | VDDQ+0.6 | V | 1 |
| Clock Input Crossing Point Voltage; CK and CK | Vıx | 0.5*VDDQ-0.2 | - | 0.5*VDDQ+0.2 | V | 2 |

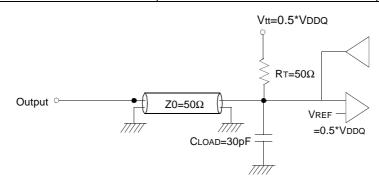
Note: 1. VID is the magnitude of the difference between the input level on CK and the input level on CK

2. The value of Vix is expected to equal 0.5*VDDQ of the transmitting device and must track variations in the DC level of the same



AC OPERATING TEST CONDITIONS (VDD=2.5V±0.125V, TA= 0 to 65°C)

| Parameter | Value | Unit | Note |
|--|---------------------|------|------|
| Input reference voltage for CK(for single ended) | 0.50*VDDQ | V | |
| CK and CK signal maximum peak swing | 1.5 | V | |
| CK signal minimum slew rate | 1.0 | V/ns | |
| Input Levels(VIH/VIL) | VREF+0.35/VREF-0.35 | V | |
| Input timing measurement reference level | VREF | V | |
| Output timing measurement reference level | Vtt | V | |
| Output load condition | See Fig.1 | | |



(Fig. 1) Output Load Circuit

CAPACITANCE (VDD=3.3V, TA= 25°C, f=1MHz)

| Parameter | Symbol | Min | Max | Unit |
|--|--------|-----|-----|------|
| Input capacitance(CK, CK) | CIN1 | 1.0 | 5.0 | pF |
| Input capacitance(A0~A10, BA0~BA1) | CIN2 | 1.0 | 4.0 | pF |
| Input capacitance (CKE, CS, RAS, CAS, WE) | Сімз | 1.0 | 4.0 | pF |
| Data & DQS input/output capacitance(DQ0~DQ31) | Соит | 1.0 | 6.5 | pF |
| Input capacitance(DM0 ~ DM3) | CIN4 | 1.0 | 6.5 | pF |

DECOUPLING CAPACITANCE GUIDE LINE

Recommended decoupling capacitance added to power line at board.

| Parameter | Symbol | Value | Unit |
|--|--------|------------|------|
| Decoupling Capacitance between VDD and Vss | CDC1 | 0.1 + 0.01 | uF |
| Decoupling Capacitance between VDDQ and VSSQ | CDC2 | 0.1 + 0.01 | uF |

Note: 1. VDD and VDDQ pins are separated each other.

All VDD pins are connected in chip. All VDDQ pins are connected in chip.

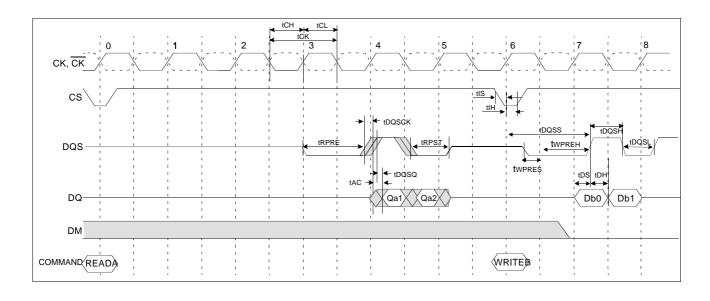
2. Vss and Vssq pins are separated each other

All Vss pins are connected in chip. All Vssq pins are connected in chip.



AC CHARACTERISTICS

| Parameter | | Cumbal | -3 | 3 | -4 | 0 | -45 | 5 | -50 |) | -55 | 5 | -60 | | l lmit | Note |
|----------------------------|----------|----------------|--------------|------|--------------|------|--------------|------|--------------|------|--------------|------|--------------|------|--------|------|
| Parameter | | Symbol | Min | Max | Unit | Note |
| | CL=2 | | - | | - | | 10 | | 10 | | 10 | | 10 | | ns | |
| CK cycle time | CL=3 | 4 | - | 7 | - | 7 | 5.0 | 10 | 5.0 | 10 | 5.5 | 10 | 6.0 | 10 | ns | |
| CK cycle time | CL=4 | tcĸ | - | , | 4.0 | ′ | 4.5 | 10 | - | 10 | - | 10 | - | 10 | ns | |
| | CL=5 | | 3.3 | | - | | - | | - | | - | | - | | ns | |
| CK high level width | | tсн | 0.45 | 0.55 | 0.45 | 0.55 | 0.45 | 0.55 | 0.45 | 0.55 | 0.45 | 0.55 | 0.45 | 0.55 | tCK | |
| CK low level width | | tcl | 0.45 | 0.55 | 0.45 | 0.55 | 0.45 | 0.55 | 0.45 | 0.55 | 0.45 | 0.55 | 0.45 | 0.55 | tCK | |
| DQS out access time from | n CK | t DQSCK | -0.6 | 0.6 | -0.6 | 0.6 | -0.7 | 0.7 | -0.7 | 0.7 | -0.75 | 0.75 | -0.75 | 0.75 | ns | |
| Output access time from | CK | tac | -0.6 | 0.6 | -0.6 | 0.6 | -0.7 | 0.7 | -0.7 | 0.7 | -0.75 | 0.75 | -0.75 | 0.75 | ns | |
| Data strobe edge to Dout | edge | toqsq | - | 0.35 | - | 0.4 | - | 0.45 | - | 0.45 | - | 0.5 | - | 0.5 | ns | 1 |
| Read preamble | | t rpre | 0.9 | 1.1 | 0.9 | 1.1 | 0.9 | 1.1 | 0.9 | 1.1 | 0.9 | 1.1 | 0.9 | 1.1 | tCK | |
| Read postamble | | t RPST | 0.4 | 0.6 | 0.4 | 0.6 | 0.4 | 0.6 | 0.4 | 0.6 | 0.4 | 0.6 | 0.4 | 0.6 | tCK | |
| CK to valid DQS-in | | togss | 0.85 | 1.15 | 0.85 | 1.15 | 0.8 | 1.2 | 0.8 | 1.2 | 0.75 | 1.25 | 0.75 | 1.25 | tCK | |
| DQS-In setup time | | twpres | 0 | | 0 | - | 0 | - | 0 | - | 0 | - | 0 | - | ns | |
| DQS-in hold time | | twpreh | 0.35 | - | 0.35 | - | 0.3 | - | 0.3 | - | 0.25 | - | 0.25 | - | tCK | |
| DQS write postamble | | twpst | 0.4 | 0.6 | 0.4 | 0.6 | 0.4 | 0.6 | 0.4 | 0.6 | 0.4 | 0.6 | 0.4 | 0.6 | tCK | |
| DQS-In high level width | | tdqsh | 0.4 | 0.6 | 0.4 | 0.6 | 0.4 | 0.6 | 0.4 | 0.6 | 0.4 | 0.6 | 0.4 | 0.6 | tCK | |
| DQS-In low level width | | togsl | 0.4 | 0.6 | 0.4 | 0.6 | 0.4 | 0.6 | 0.4 | 0.6 | 0.4 | 0.6 | 0.4 | 0.6 | tCK | |
| Address and Control inpu | ıt setup | tıs | 0.9 | - | 0.9 | - | 1.0 | - | 1.0 | - | 1.1 | - | 1.1 | - | ns | |
| Address and Control inpu | ıt hold | tıн | 0.9 | - | 0.9 | - | 1.0 | - | 1.0 | - | 1.1 | - | 1.1 | - | ns | |
| DQ and DM setup time to | DQS | tos | 0.35 | - | 0.4 | - | 0.45 | - | 0.45 | - | 0.5 | - | 0.5 | - | ns | |
| DQ and DM hold time to I | DQS | tон | 0.35 | - | 0.4 | - | 0.45 | - | 0.45 | - | 0.5 | - | 0.5 | - | ns | |
| | | | tCLmin | | tCLmin | | tCLmin | | tCLmin | | tCLmin | | tCLmin | | | |
| Clock half period | | thp | or tCHmin | - | ns | 1 |
| Data output hold time from | n DQS | tqн | tHP- 0.35 | - | tHP-0.4 | - | tHP- 0.45 | - | tHP- 0.45 | - | tHP-0.5 | - | tHP-0.5 | - | ns | 1 |

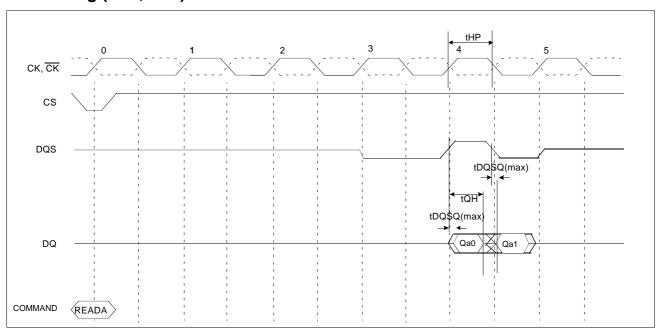




Note 1:

- The JEDEC DDR specification currently defines the output data valid window(tDV) as the time period when the data strobe and all data associated with that data strobe are coincidentally valid.
- The previously used definition of tDV(=0.35tCK) artificially penalizes system timing budgets by assuming the worst case output vaild window even then the clock duty cycle applied to the device is better than 45/55%
- A new AC timing term, tQH which stands for data output hold time from DQS is difined to account for clock duty cycle variation and replaces tDV
- tQHmin = tHP-X where
- . tHP=Minimum half clock period for any given cycle and is defined by clock high or clock low time(tCH,tCL)
- . X=A frequency dependent timing allowance account for tDQSQmax

tQH Timing (CL4, BL2)





AC CHARACTERISTICS (I)

| Parameter | C b. a.l | -33 | } | -40 | | -45 | ; | -50 |) | -55 | ; | -60 | | Unit I | Note |
|---|---------------|----------|------|----------|------|----------|------|----------|------|----------|------|----------|------|---------|------|
| Parameter | Symbol | Min | Max | Oiiit N | Note |
| Row cycle time | trc | 17 | - | 15 | - | 13 | - | 12 | - | 12 | - | 10 | - | tCK | |
| Refresh row cycle time | trfc | 19 | - | 17 | - | 15 | - | 14 | - | 14 | - | 12 | - | tCK | |
| Row active time | tras | 12 | 100K | 10 | 100K | 9 | 100K | 8 | 100K | 8 | 100K | 7 | 100K | tCK | |
| RAS to CAS delay for Read | trcdrd | 6 | - | 5 | - | 4 | - | 4 | - | 4 | - | 3 | - | tCK | |
| RAS to CAS delay for Write | trcdwr | 4 | | 3 | | 2 | | 2 | - | 2 | - | 2 | - | tCK | |
| Row precharge time | trp | 5 | - | 5 | - | 4 | - | 4 | - | 4 | - | 3 | - | tCK | |
| Row active to Row active | trrd | 3 | - | 3 | - | 2 | - | 2 | - | 2 | - | 2 | - | tCK | |
| Last data in to Row precharge @Normal Precharge | twr | 3 | - | 3 | - | 3 | - | 2 | - | 2 | - | 2 | - | tCK | 1 |
| Last data in to Row precharge @Auto Precharge | twr_a | 3 | - | 3 | - | 3 | - | 3 | - | 3 | - | 3 | - | tCK | 1 |
| Last data in to Read command | tcdlr | 2 | - | 2 | - | 2 | - | 2 | - | 2 | - | 2 | - | tCK | 1 |
| Col. address to Col. address | tccd | 1 | - | 1 | - | 1 | - | 1 | - | 1 | - | 1 | - | tCK | |
| Mode register set cycle time | t MRD | 2 | - | 2 | - | 2 | - | 2 | - | 2 | - | 2 | - | tCK | |
| Auto precharge write recovery + Precharge | tdal | 8 | - | 8 | - | 7 | - | 7 | - | 7 | - | 6 | - | tCK | |
| Exit self refresh to read com- | txsr | 200 | - | 200 | - | 200 | - | 200 | - | 200 | - | 200 | - | tCK | |
| Power down exit time | t PDEX | 1tCK+tIS | - | ns | |
| Refresh interval time | tref | 7.8 | - | 7.8 | - | 7.8 | - | 7.8 | - | 7.8 | - | 7.8 | - | us | |

Note: 1. For normal write operation, even numbers of Din are to be written inside DRAM

AC CHARACTERISTICS (II)

(Unit : Number of Clock)

K4D623238B-GC33

| Frequency | Cas Latency | tRC | tRFC | tRAS | tRCDRD | tRCDWR | tRP | tRRD | tDAL | Unit |
|------------------|-------------|-----|------|------|--------|--------|-----|------|------|------|
| 333MHz (3.3ns) | 5 | 17 | 19 | 12 | 6 | 4 | 5 | 3 | 8 | tCK |
| 250MHz (4.0ns) | 4 | 15 | 17 | 10 | 5 | 3 | 5 | 3 | 8 | tCK |
| 222MHz (4.5ns) | 4 | 13 | 15 | 9 | 4 | 2 | 4 | 2 | 7 | tCK |
| 200MHz (5.0ns) | 3 | 12 | 14 | 8 | 4 | 2 | 4 | 2 | 7 | tCK |
| 183MHz (5.5ns) | 3 | 12 | 14 | 8 | 4 | 2 | 4 | 2 | 7 | tCK |
| 166MHz (6.0ns) | 3 | 10 | 12 | 7 | 3 | 2 | 3 | 2 | 6 | tCK |

K4D623238B-GC40

| Frequency | Cas Latency | tRC | tRFC | tRAS | tRCDRD | tRCDWR | tRP | tRRD | tDAL | Unit |
|------------------|-------------|-----|------|------|--------|--------|-----|------|------|------|
| 250MHz (4.0ns) | 4 | 15 | 17 | 10 | 5 | 3 | 5 | 3 | 8 | tCK |
| 222MHz (4.5ns) | 4 | 13 | 15 | 9 | 4 | 2 | 4 | 2 | 7 | tCK |
| 200MHz (5.0ns) | 3 | 12 | 14 | 8 | 4 | 2 | 4 | 2 | 7 | tCK |
| 183MHz (5.5ns) | 3 | 12 | 14 | 8 | 4 | 2 | 4 | 2 | 7 | tCK |
| 166MHz (6.0ns) | 3 | 10 | 12 | 7 | 3 | 2 | 3 | 2 | 6 | tCK |

K4D623238B-GC45

| Frequency | Cas Latency | tRC | tRFC | tRAS | tRCDRD | tRCDWR | tRP | tRRD | tDAL | Unit |
|------------------|-------------|-----|------|------|--------|--------|-----|------|------|------|
| 222MHz (4.5ns) | 4 | 13 | 15 | 9 | 4 | 2 | 4 | 2 | 7 | tCK |
| 200MHz (5.0ns) | 3 | 12 | 14 | 8 | 4 | 2 | 4 | 2 | 7 | tCK |
| 183MHz (5.5ns) | 3 | 12 | 14 | 8 | 4 | 2 | 4 | 2 | 7 | tCK |
| 166MHz (6.0ns) | 3 | 10 | 12 | 7 | 3 | 2 | 3 | 2 | 6 | tCK |



K4D623238B-GC50

| Frequency | Cas Latency | tRC | tRFC | tRAS | tRCDRD | tRCDWR | tRP | tRRD | tDAL | Unit |
|------------------|-------------|-----|------|------|--------|--------|-----|------|------|------|
| 200MHz (5.0ns) | 3 | 12 | 14 | 8 | 4 | 2 | 4 | 2 | 7 | tCK |
| 183MHz (5.5ns) | 3 | 12 | 14 | 8 | 4 | 2 | 4 | 2 | 7 | tCK |
| 166MHz (6.0ns) | 3 | 10 | 12 | 7 | 3 | 2 | 3 | 2 | 6 | tCK |

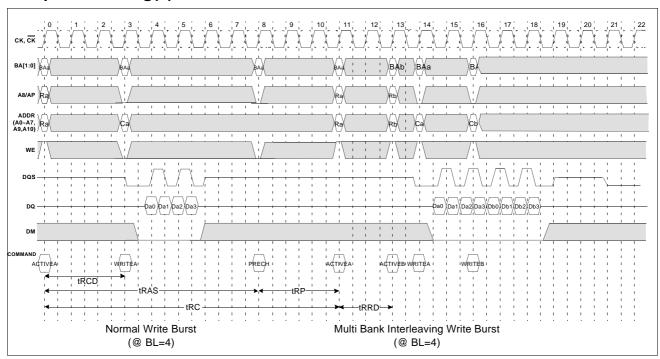
K4D623238B-GC55

| Frequency | Cas Latency | tRC | tRFC | tRAS | tRCDRD | tRCDWR | tRP | tRRD | tDAL | Unit |
|------------------|-------------|-----|------|------|--------|--------|-----|------|------|------|
| 183MHz (5.5ns) | 3 | 12 | 14 | 8 | 4 | 2 | 4 | 2 | 7 | tCK |
| 166MHz (6.0ns) | 3 | 10 | 12 | 7 | 3 | 2 | 3 | 2 | 6 | tCK |

K4D623238B-GC60

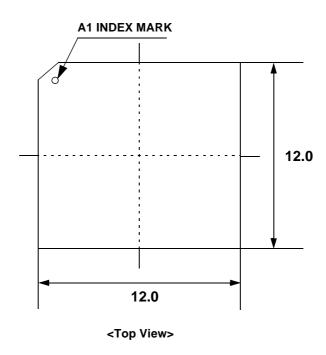
| Frequency | Cas Latency | tRC | tRFC | tRAS | tRCDRD | tRCDWR | tRP | tRRD | tDAL | Unit |
|------------------|-------------|-----|------|------|--------|--------|-----|------|------|------|
| 166MHz (6.0ns) | 3 | 10 | 12 | 7 | 3 | 2 | 3 | 2 | 6 | tCK |

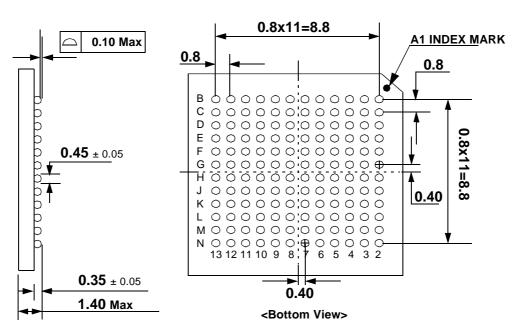
Simplified Timing(2) @ BL=4





PACKAGE DIMENSIONS (144-Ball FBGA)





Unit: mm



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